

Search Notes**Application No.**

09/839,416

Examiner

Mohamed Charioui

Applicant(s)

ISHIDA, KOZO

Art Unit

2857

SEARCHED

Class	Subclass	Date	Examiner
702	64, 65, 110, 183	3/18/2004	MC
702	118-125	3/19/2004	MC
714	724-727	3/19/2004	MC
324	73.1	3/19/2004	MC
324	763-765	3/19/2004	MC
Search	updated	9/10/2004	MC
714	30, 733	9/10/2004	MC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
702	120	9/10/2004	MC
714	30	9/10/2004	MC

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East: (semiconductor or semiconductors or "integrated circuits" or "IC") and "shift register" and ((selector or selecting or selected or selects) with buffer) and "flip-flop" and (tester or testing or tested or tests)	3/18/2004	MC
East: ((tristate near (buffer or buffers)) with (impedance or impedances or resistor or resistors) and ("flip-flop" or "flip-flops"))	3/19/2004	MC
IEEE: search by inventor's name.	3/19/2004	MC
Text search updated	9/10/2004	MC